

# HLX 20125025 A03

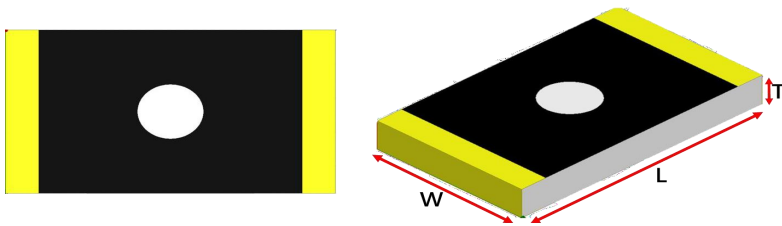
## Features

1. Surface Mounted Devices with a small dimension of 2.0 x 1.25 x 0.25 mm<sup>3</sup> meet future miniaturization trend.
2. Embedded and (Low Temperature Co-fired Ceramic) technology is able to future integrate with system design as well as beautifying the housing of final product.
3. High Stability in Temperature / Humidity Change

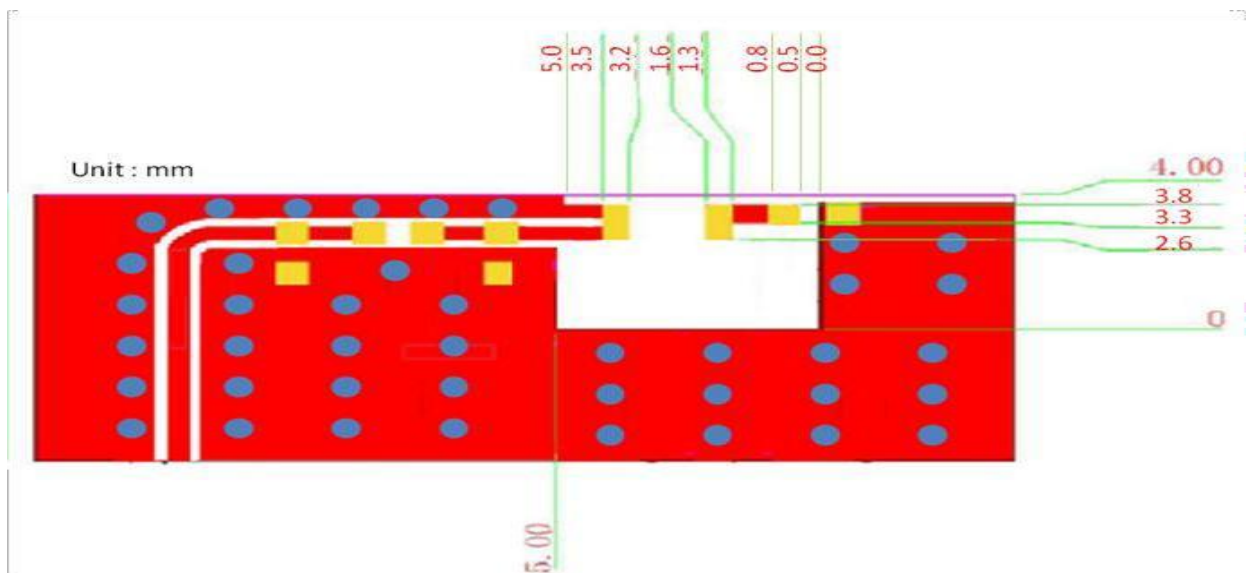
## Applications

1. Bluetooth
2. Wireless LAN
3. HornRF
4. ISM band 2.4GHz wireless applications

## Dimensions (Unit: mm)

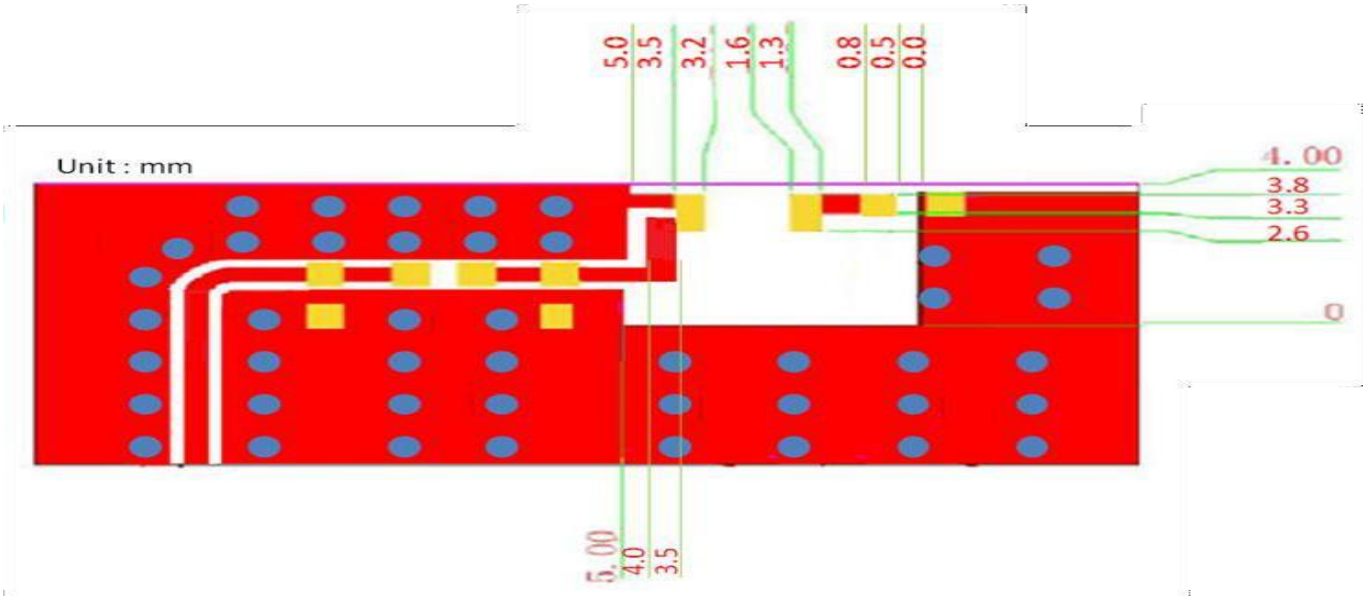


	Dimension (mm)
<b>L</b>	2.0 ± 0.20
<b>W</b>	1.2 ± 0.20
<b>T</b>	0.25 ± 0.05

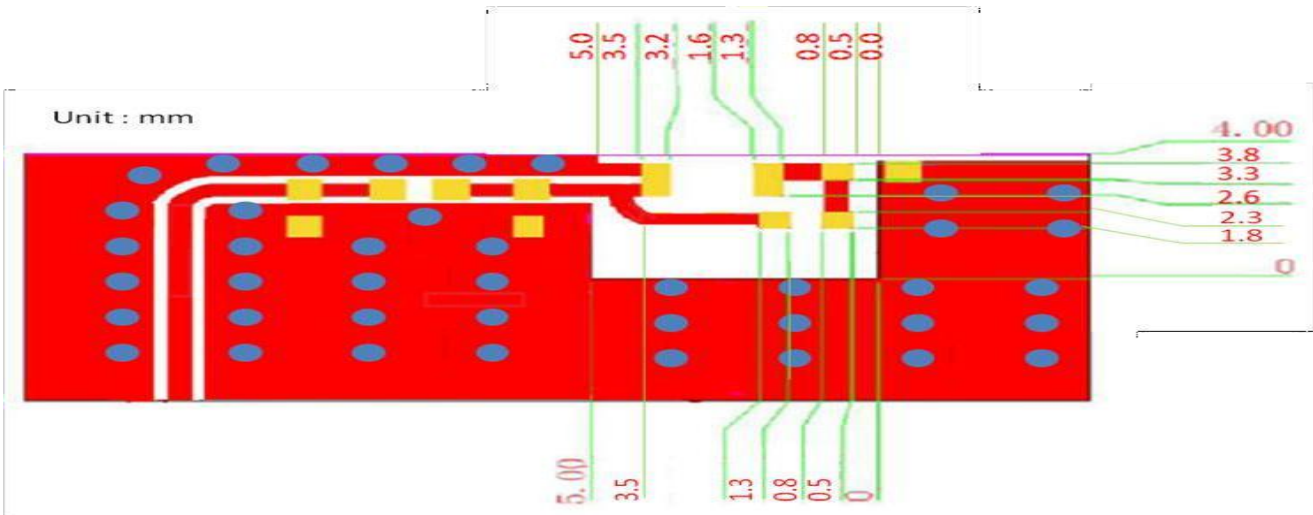


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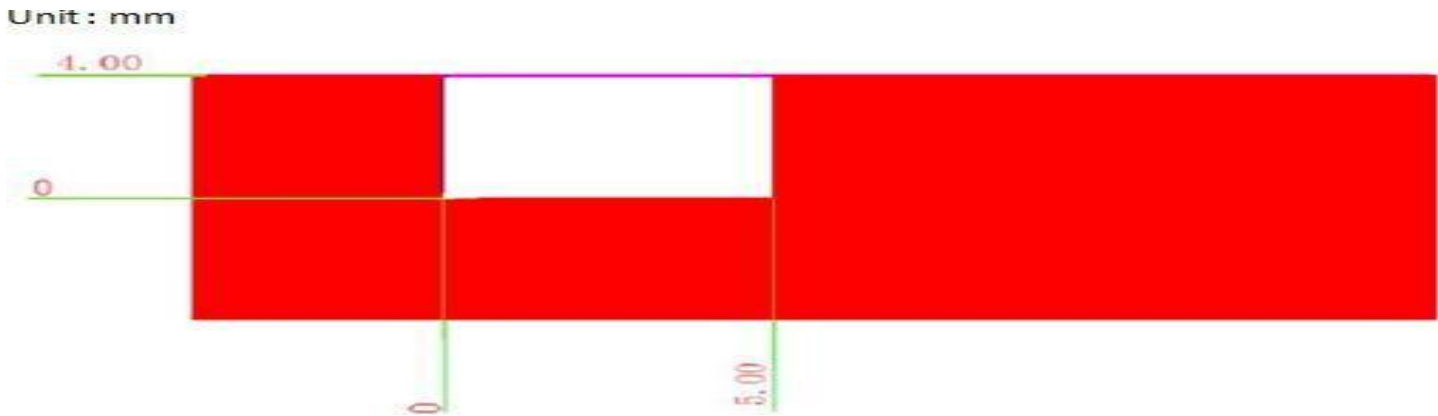
Type2:



Type3:

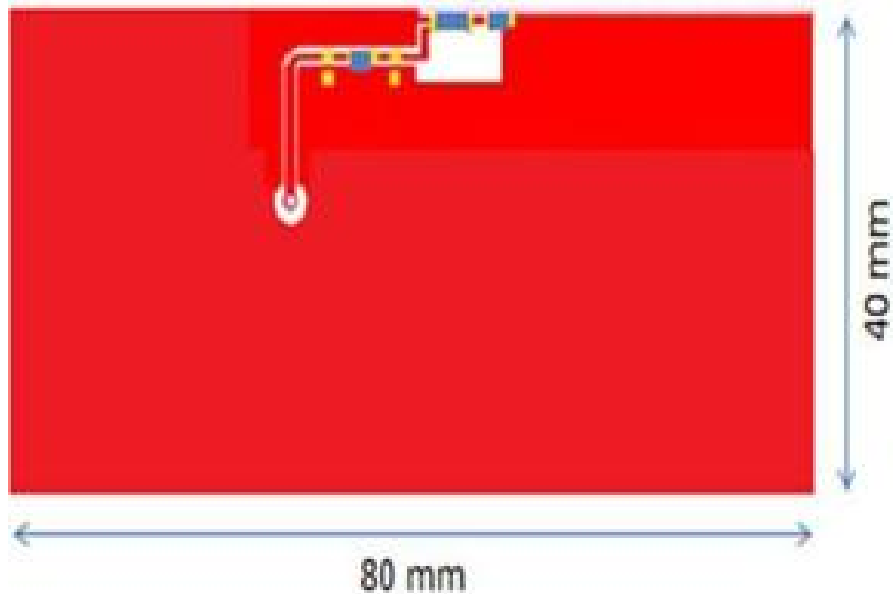


PCB Bottom View :



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## Evaluation Board and Matching Circuits

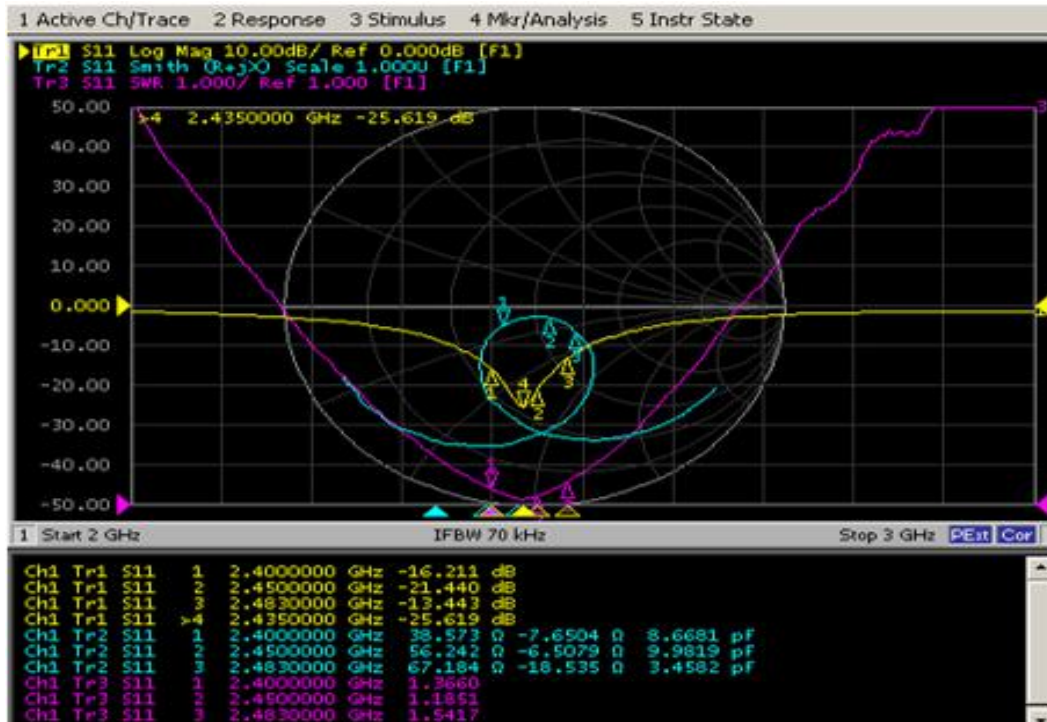


## Electrical Characteristics

Specification		
Part Number	ANTD21W02-X1	
Central Frequency	2450	MHz
Bandwidth	90 (Min.)	MHz
Return Loss	-10 (Max)	dB
Peak Gain	2.16	dBi
Impedance	50	$\Omega$
Operating Temperature	-40~+85	$^{\circ}\text{C}$
Maximum Power	1	W
Resistance to Soldering Heats	10 ( @ 260 $^{\circ}\text{C}$ )	sec.
Polarization	Linear	
Azimuth Beamwidth	Omni-directional	
Termination	Cu / Sn (Leadless)	

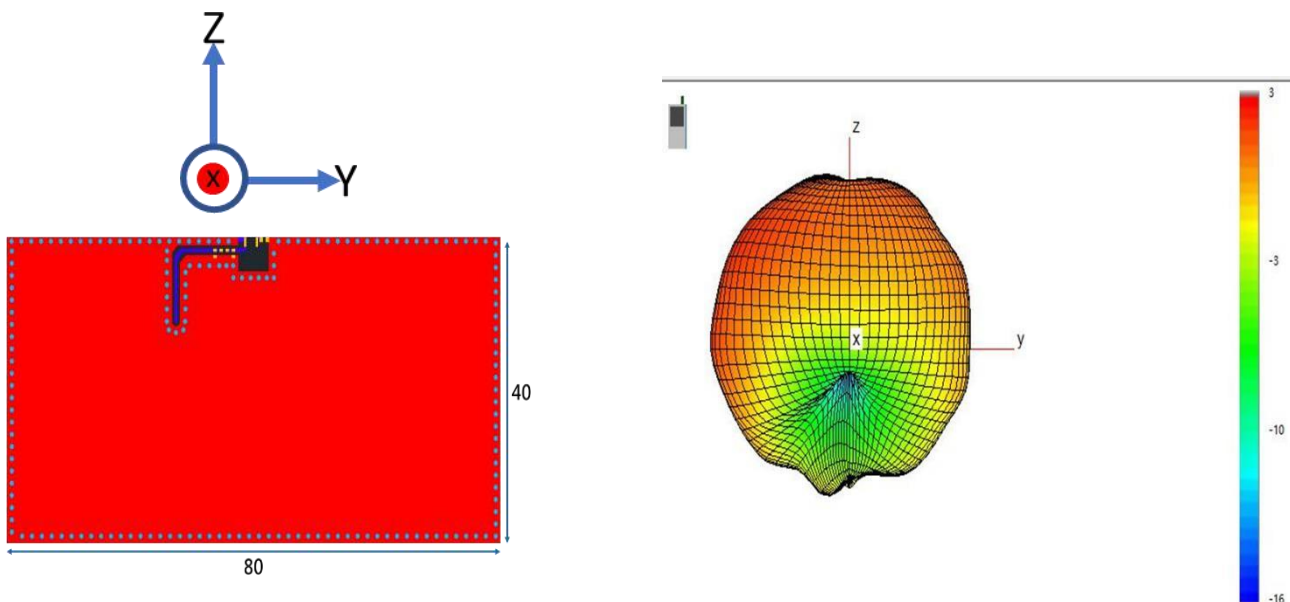
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## Characteristic curve



## Radiation Pattern

Frequency (MHz)	2400	2450	2500
Efficiency (dB)	-1.42	-1.24	-1.47
Efficiency (%)	71	75	71
Peak Gain (dBi)	2.11	2.06	1.94



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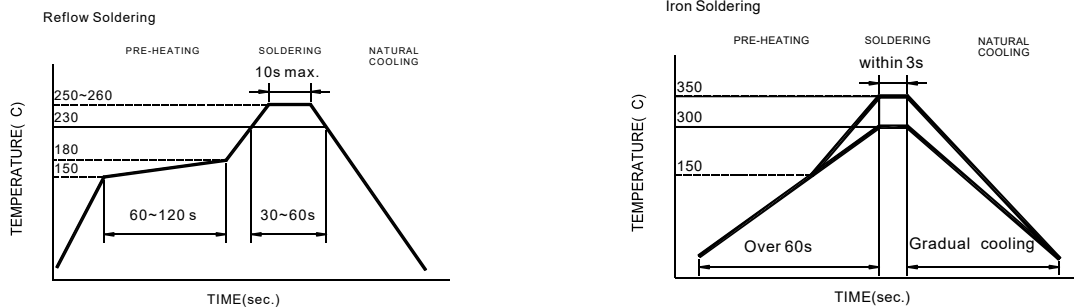
## Reliability and Test Condictions

ITEM	REQUIREMENTS	TEST CONDITION															
Solderability	1. Wetting shall exceed 90% coverage 2. No visible mechanical damage  	Pre-heating temperature:150°C/60sec. Solder temperature:230±5°C Duration:4±1sec. Solder:Sn-Ag3.0-Cu0.5 Flux for lead free: rosin															
Solder heat Resistance	1. No visible mechanical damage 2. Central Freq. change :within ± 6%  	Pre-heating temperature:150°C/60sec. Solder temperature:260±5°C Duration:10±0.5sec. Solder:Sn-Ag3.0-Cu0.5 Flux for lead free: rosin															
Component Adhesion (Push test)	1. No visible mechanical damage	The device should be reflow soldered(230±5°C for 10sec.) to a tinned copper substrate A dynameter force gauge should be applied the side of the component. The device must with-ST-F 0.5 Kg without failure of the termination attached to component.															
Component Adhesion (Pull test)	1. No visible mechanical damage	Insert 10cm wire into the remaining open eye bend ,the ends of even wire lengths upward and wind together. Terminal shall not be remarkably damaged.															
Thermal shock	1. No visible mechanical damage 2. Central Freq. change :within ±6%  <table border="1"> <thead> <tr> <th>Phase</th> <th>Temperature(°C)</th> <th>Time(min)</th> </tr> </thead> <tbody> <tr> <td>1</td> <td>+85±5 °C</td> <td>30±3</td> </tr> <tr> <td>2</td> <td>Room Temperature</td> <td>Within 3sec</td> </tr> <tr> <td>3</td> <td>-40±2 °C</td> <td>30±3</td> </tr> <tr> <td>4</td> <td>Room Temperature</td> <td>Within 3sec</td> </tr> </tbody> </table>	Phase	Temperature(°C)	Time(min)	1	+85±5 °C	30±3	2	Room Temperature	Within 3sec	3	-40±2 °C	30±3	4	Room Temperature	Within 3sec	+85 °C=>30±3min -40 °C=>30±3min Test cycle:10 cycles The chip shall be stabilized at normal condition for 2~3 hours before measuring.
Phase	Temperature(°C)	Time(min)															
1	+85±5 °C	30±3															
2	Room Temperature	Within 3sec															
3	-40±2 °C	30±3															
4	Room Temperature	Within 3sec															
Resistance to High Temperature	1. No visible mechanical damage 2. Central Freq. change :within ±6% 3. No disconnection or short circuit.	Temperature: 85±5°C Duration: 1000±12hrs The chip shall be stabilized at normal condition for 2~3 hours before measuring.															
Resistance to Low Temperature	1. No visible mechanical damage 2. Central Freq. change :within ±6% 3. No disconnection or short circuit.	Temperature:-40±5°C Duration: 1000±12hrs The chip shall be stabilized at normal condition for 2~3 hours before measuring.															
Humidity	1. No visible mechanical damage 2. Central Freq. change :within ±6% 3. No disconnection or short circuit.	Temperature: 40±2°C Humidity: 90% to 95% RH Duration: 1000±12hrs The chip shall be stabilized at normal condition for 2~3 hours before measuring.															

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## Soldering and Mounting

Mildly activated rosin fluxes are preferred. The minimum amount of solder can lead to damage from the stresses caused by the difference in coefficients of expansion between solder, chip and substrate. The terminations are suitable for all wave and re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.



Recommended temperature profiles for re-flow soldering in Figure 1.

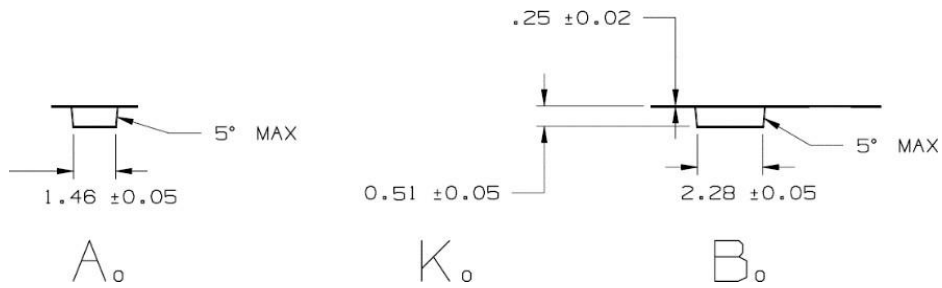
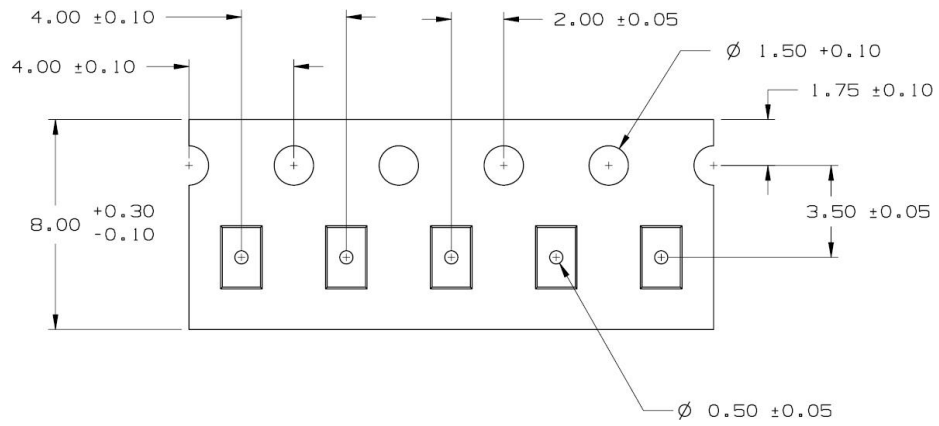
Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended.

- Preheat circuit and products to 150°C
- Never contact the ceramic with the iron tip
- Use a 20 watt soldering iron with tip diameter of 1.0mm
- 280°C tip temperature (max)
- 1.0mm tip diameter (max)
- Limit soldering time to 3 sec.

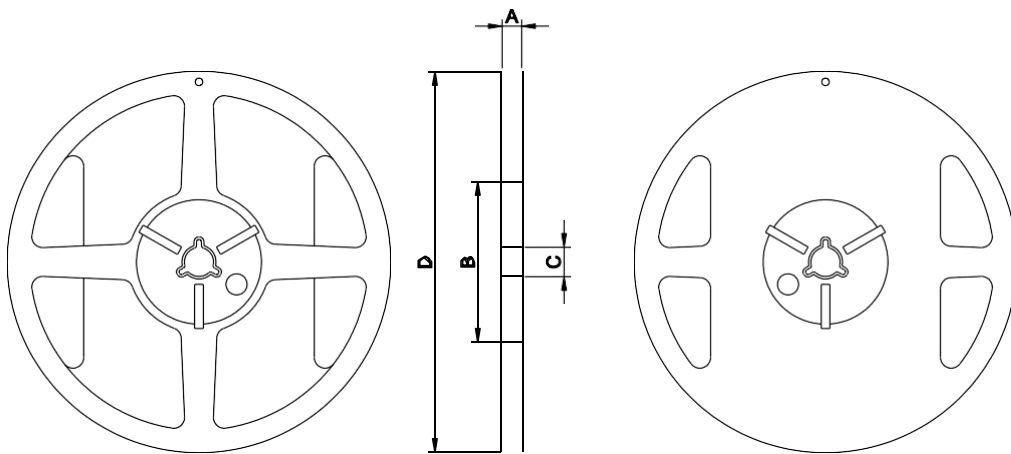
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## Packaging Information

### ◆Tape Specification:



### ◆Reel Specification: (7", $\phi 180$ mm)



7" x 8 mm

Tape Width(mm)	A(mm)	B(mm)	C(mm)	D(mm)	Chip/Reel(pcs)
8	$9.0 \pm 0.5$	$60 \pm 2$	$13.5 \pm 0.5$	$178 \pm 2$	6000

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## Storage and Transportation Information

### Storage Conditions

To maintain the solderability of terminal electrodes:

1. Temperature and humidity conditions: -10~ 40°C and 30~70% RH.
2. Recommended products should be used within 6 months from the time of delivery.
3. The packaging material should be kept where no chlorine or sulfur exists in the air.

### Transportation Conditions

1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
3. Bulk handling should ensure that abrasion and mechanical shock are minimized.